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Application/Control No.	Applicant(s)/Patent under Reexamination
10/674,464	CHU ET AL.
Examiner	Art Unit
Leo B. Tentoni	1732

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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
INVENTOR NAME SEARCH	7/23/05	LBT
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWEN, IBM_TDB) - SEE SEARCH HISTORY PRINTOUT		LBT